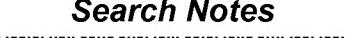


Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/680,867	FUKAYA ET AL.
	Examiner	Art Unit
	Lien T. Tran	1794

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
interference searched		9/5/2008	LT